


Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/081,724	LAVELLE ET AL.	
	Examiner	Art Unit	
	Eva Yi Zheng	2611	

ISSUE CLASSIFICATION										
ORIGINAL					CROSS REFERENCE(S)					
CLASS		SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
375		141			375	130	145			
INTERNATIONAL CLASSIFICATION					370	469	466	342		
H	0	4	B	1/69						
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<i>Ey</i> Eva Zheng 3/27/07 (Assistant Examiner) (Date)	<i>Chieh M. F.</i> CHIEH M. FAN SUPERVISORY PATENT EXAMINER (P. Examiner) (Date)	Total Claims Allowed: 7 O.G. Print Claim(s) 12 O.G. Print Fig. 1
(Legal Instruments Examiner) (Date)	3/28/07	

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant				<input type="checkbox"/> CPA				<input type="checkbox"/> T.D.				<input type="checkbox"/> R.1.47			
Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original		
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